

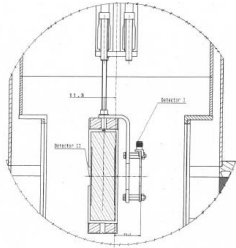
A detailed wireframe 3D model of the S483 Diamond Irradiation Test facility. The model shows a large, circular, multi-layered structure, likely a synchrotron or storage ring, with various internal components and support structures. The structure is rendered in a light gray wireframe style, allowing for a clear view of its complex geometry.

Data Analysis of S483 Diamond Irradiation Tests

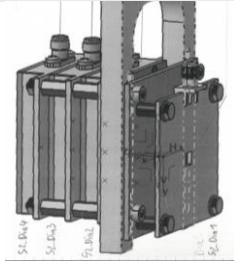
Matteo Alfonsi (GSI – SFRS System Planning)

- Diamond detectors @ SFRS should provide intensity information also during the maximum beam intensity, in case of specific measurements
- E.g. we expect to irradiate this detector with $\sim 10^9$ ions/mm² in a calibration for a cross-section measurement
- In Feb 2021 a polycrystalline Diamond (pcDIA) sample has been irradiated with Pb (1GeV/n) @ FRS S1. Comparable irradiation with U in Mar 2021.
- Periods of high intensity irradiation alternated with low rate periods in which the performance of the sample has been measured.
- Bunches of signal waveforms have been acquired with a high bandwidth oscilloscope, to check for degradation of signal properties

Irradiation Test Setup

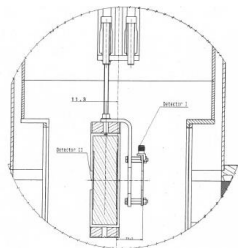


Ionization chamber (IC),
Polycrystalline diamond (pcDIA)
to be irradiated

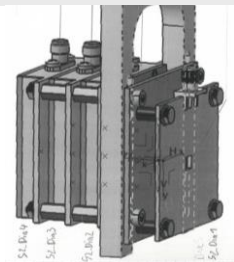


Stack of
single-crystal
diamond (scDIA)
used as trigger

Irradiation Test Setup

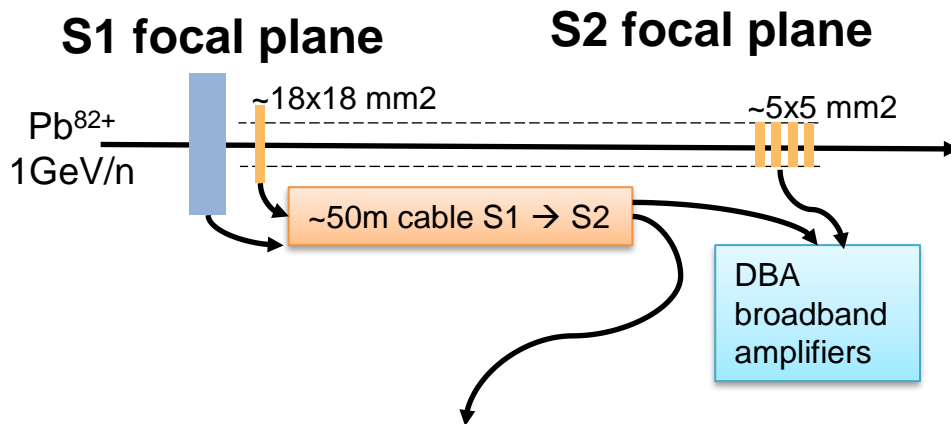


Ionization chamber (IC), Polycrystalline diamond (pcDIA)

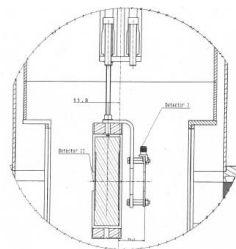


Stack of single-crystal diamond (scDIA), used as trigger

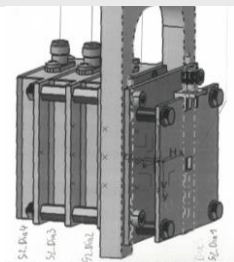
- Electronics at S2, amplifier only after long cable



Irradiation Test Setup



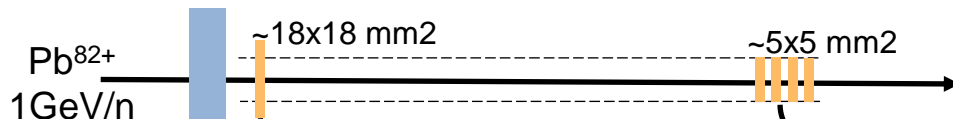
Ionization chamber (IC), Polycrystalline diamond (pcDIA)



Stack of single-crystal diamond (scDIA), used as trigger

S1 focal plane

S2 focal plane



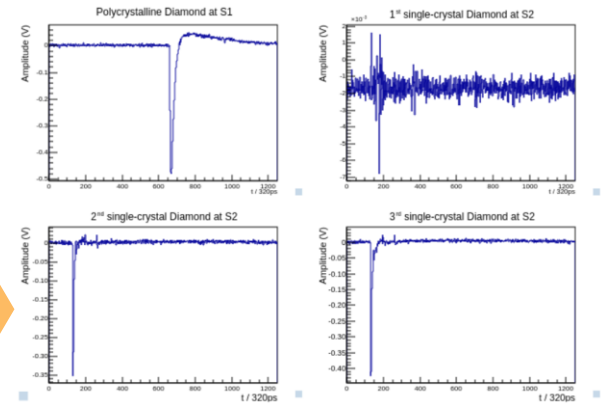
~50m cable S1 → S2

DBA broadband amplifiers

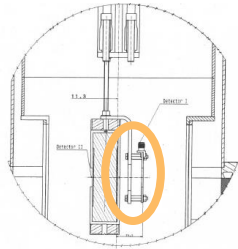
MBS DAQ



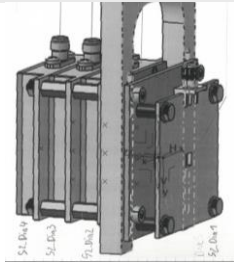
- Electronics at S2, amplifier only after long cable
- Both MBS DAQ & waveform saving



Go4 analysis
• Calculate integrated irradiation

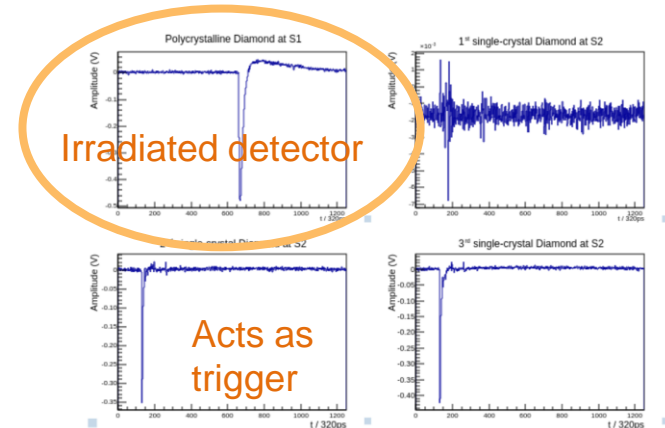


Ionization chamber (IC),
Polycrystalline diamond (pcDIA)
HV -300V

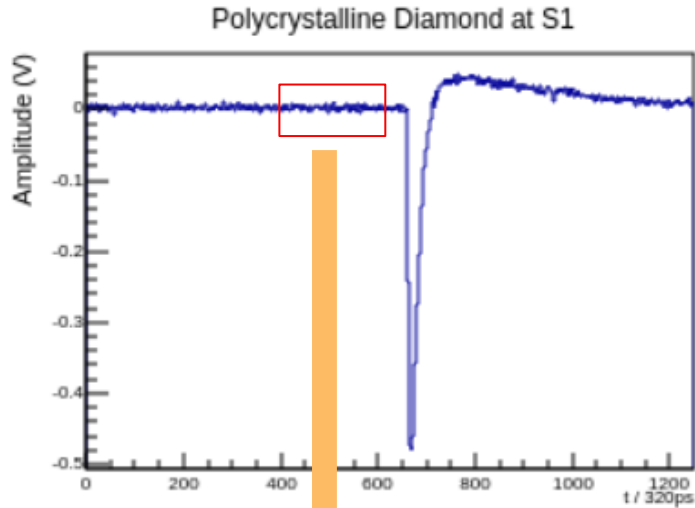


Stack of
single-crystal
diamond (scDIA),
2nd of the stack
as trigger

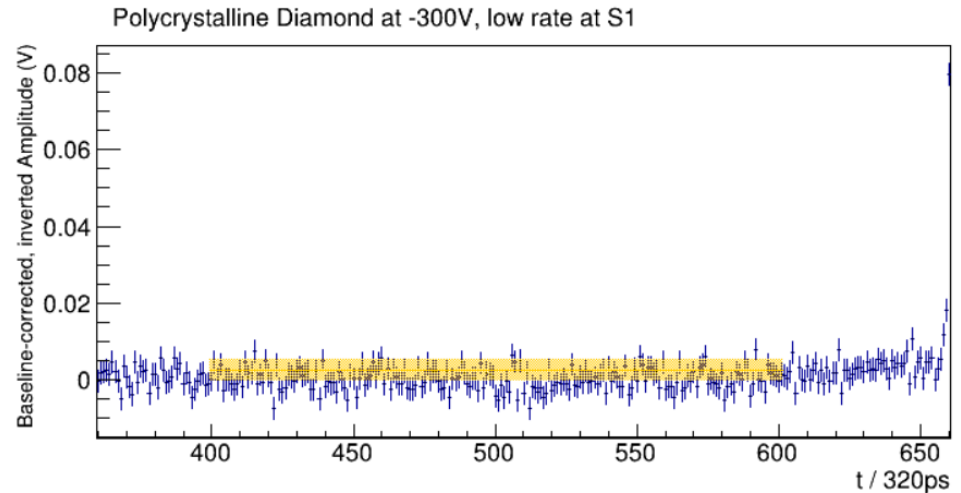
Waveform processing tools development with first low rate dataset



Waveform processing



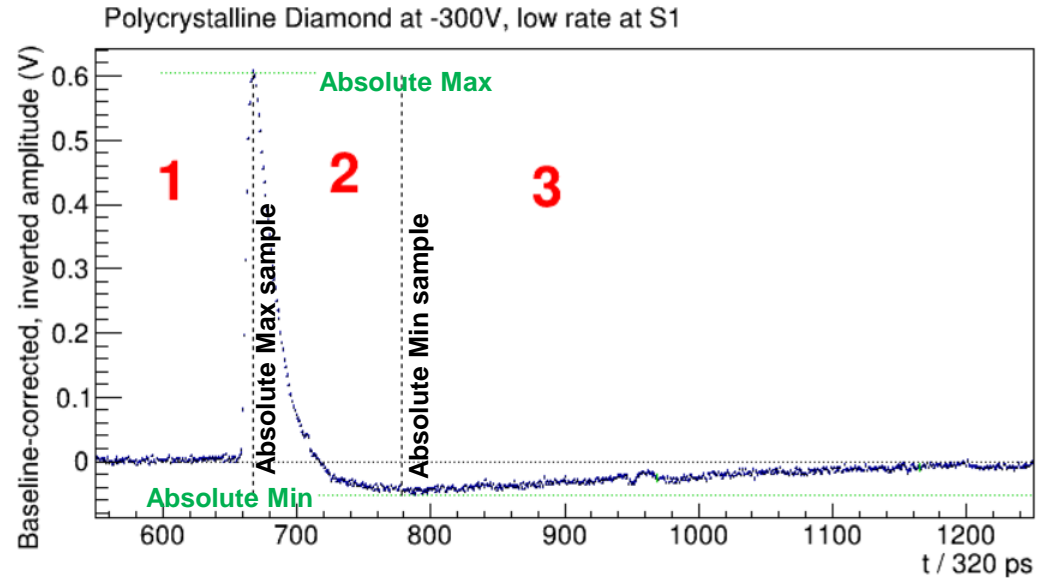
- Baseline calculated just before the signal
- Baseline-corrected signal inverted



- “noise around baseline”
crucial role for next steps

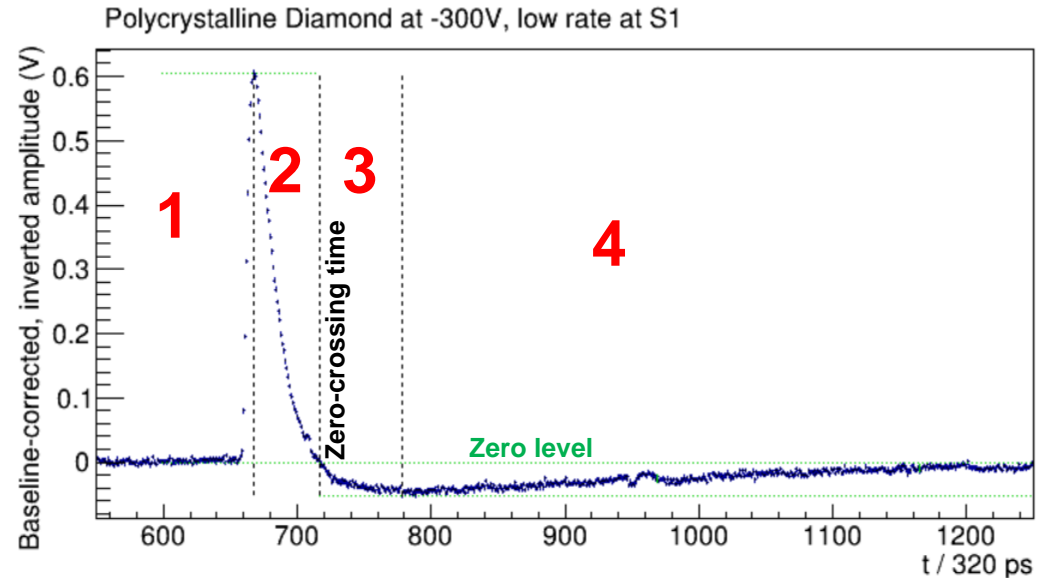
Signal shape descriptors (I)

- Absolute Min & Max searched
- Corresponding samples divide the waveform in three regions

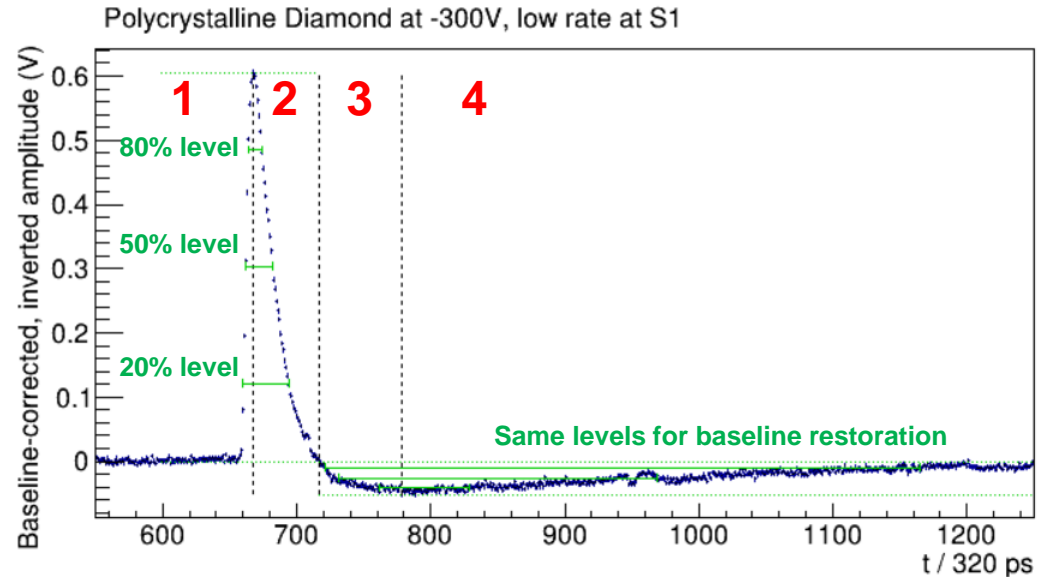


Signal shape descriptors (II)

- Between Min and Max, Zero-crossing time as weighed-average time
- Weight is function of the distance to zero level, normalized to signal noise

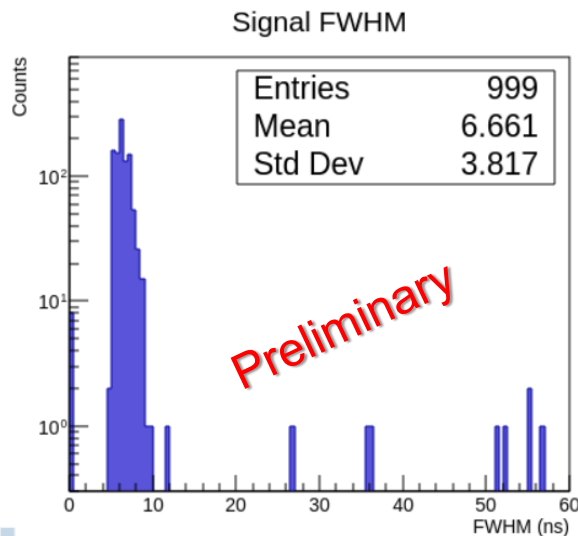
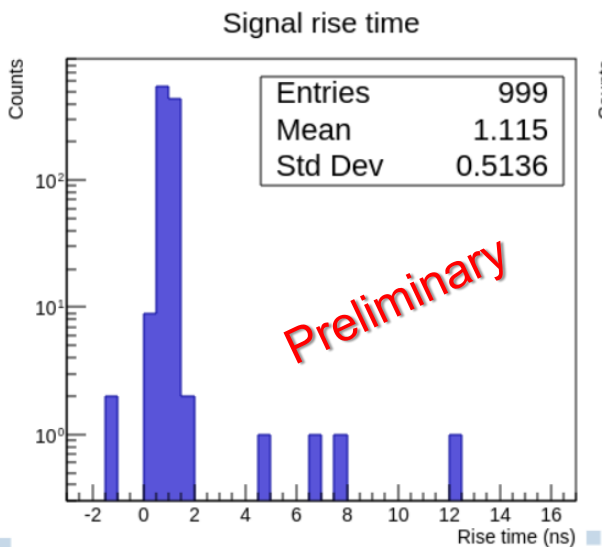


- Each region searched for the crossing-time of the 20%-, 50%- and 80%-level of the Max and the Min (for the baseline restoration)
- The same weighed average approach is used
- Quantities such as Rising Time, FWHW, etc., are built

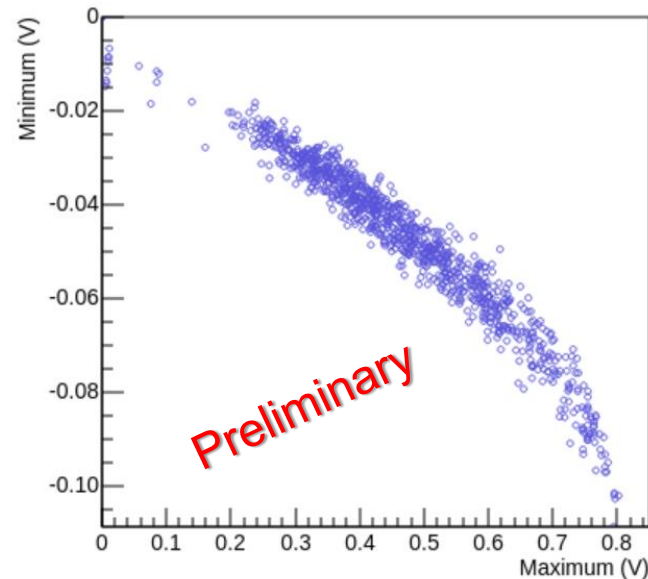


First low rate dataset

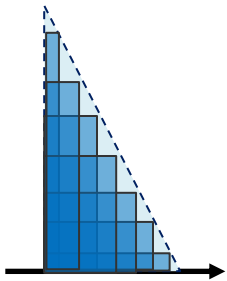
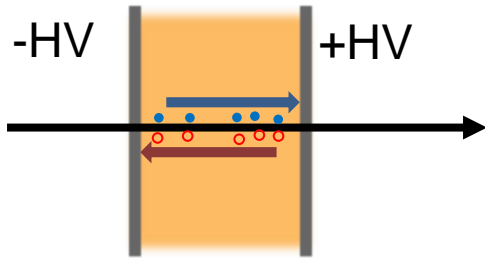
- Timing characteristics (expected and needed fast signals)



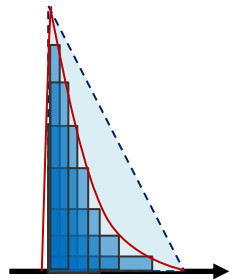
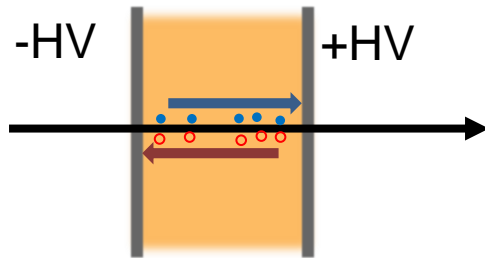
- Maximum and minimum correlated



- Ions cross diamond volume in the same direction of drifting charges

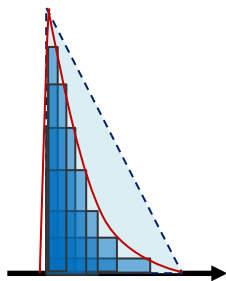
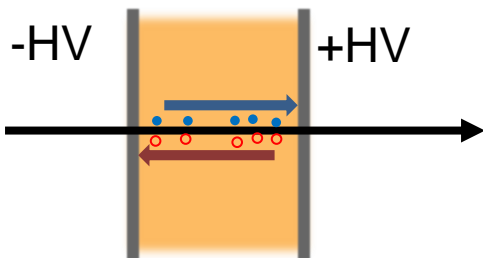


- Ions cross diamond volume in the same direction of drifting charges



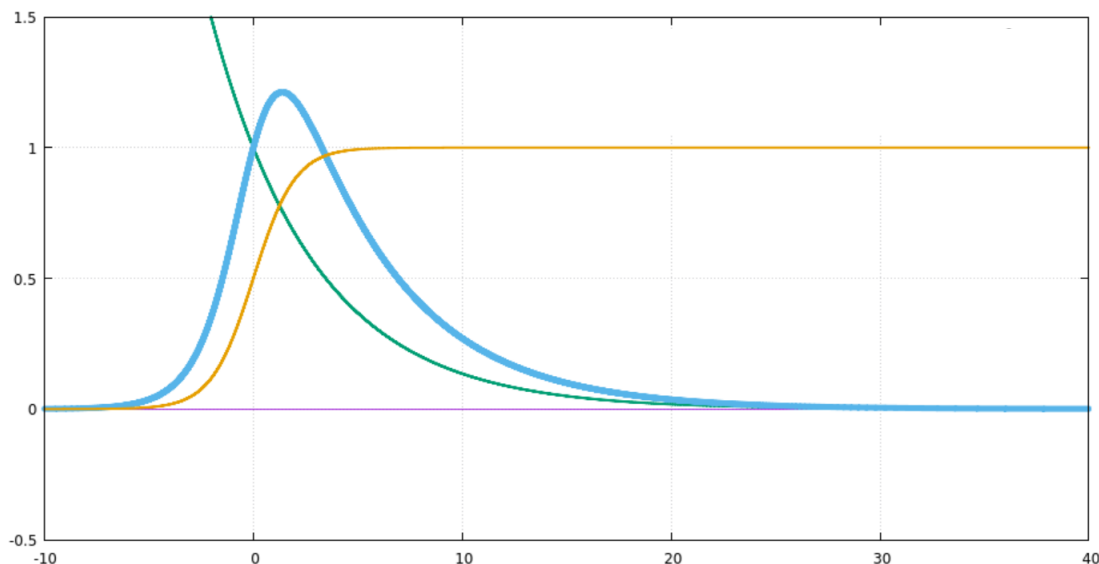
Defects in pcDIA traps especially charges that have to drift the longest

- Ions cross diamond volume in the same direction of drifting charges

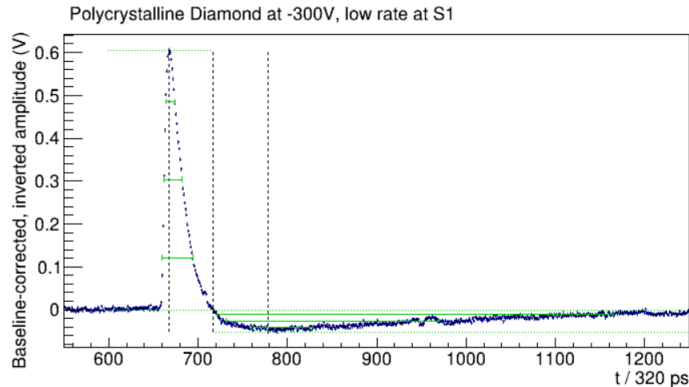


Defects in pcDIA traps especially charges that have to drift the longest

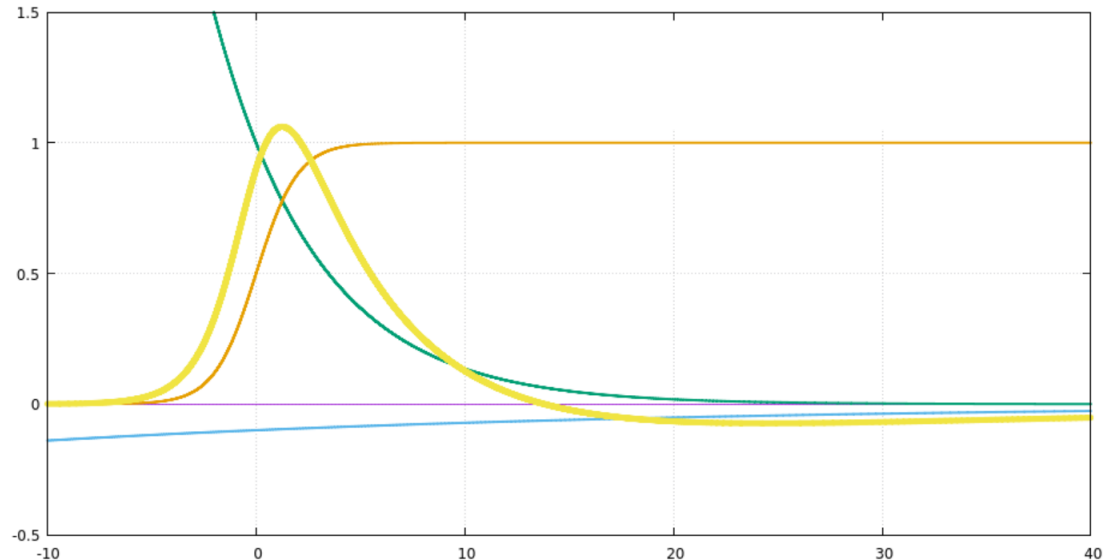
$$f(t|A, \sigma, t_0, \tau) = \frac{Ae^{-\frac{t-t_0}{\tau}}}{1 + e^{-\frac{t-t_0}{\sigma}}}$$



However our signal is bipolar!
(very likely feature of the preamp, verification ongoing)



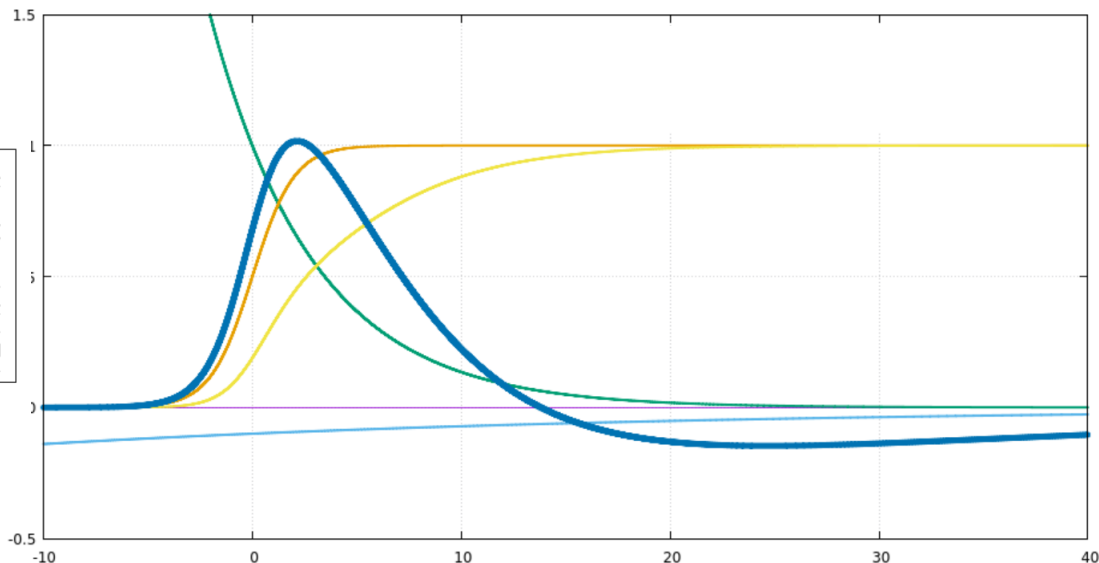
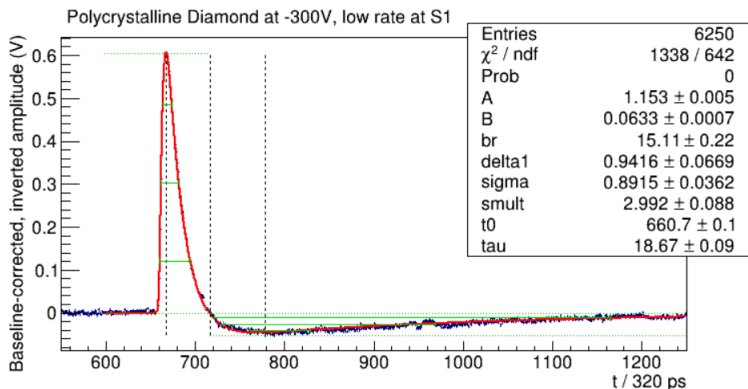
$$f(t|A, B, b_r, \sigma, t_0, \tau) = \frac{A(e^{-\frac{t-t_0}{\tau}} - B e^{-\frac{t-t_0}{\tau \cdot b_r}})}{1 + e^{-\frac{t-t_0}{\sigma}}}$$



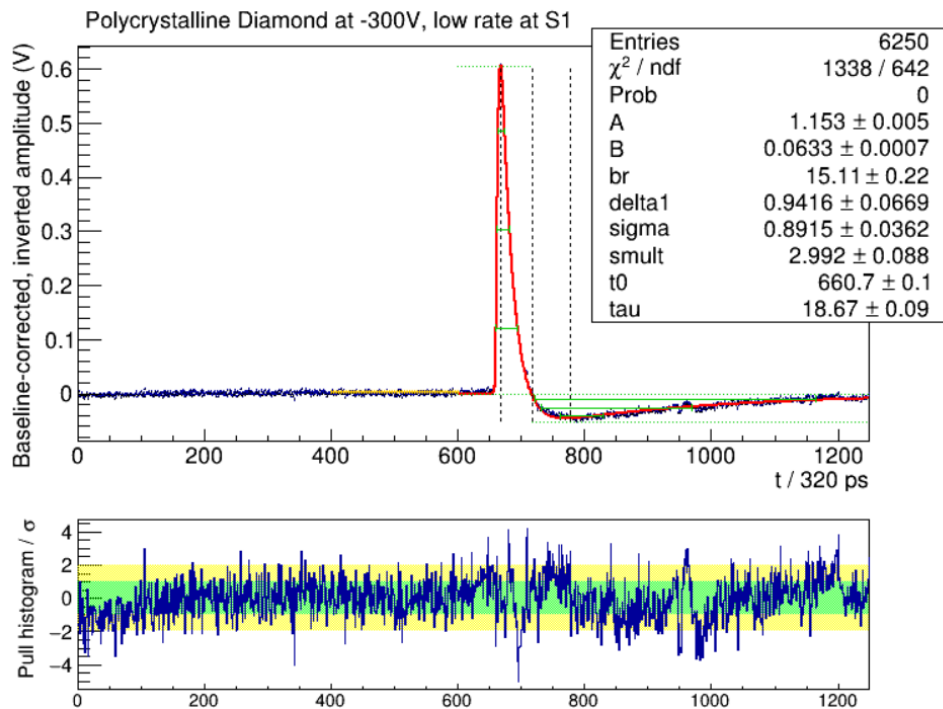
Signal model

A further sigmoid term is needed to better fit the rising edge near the peak.
No physics motivation ☹️

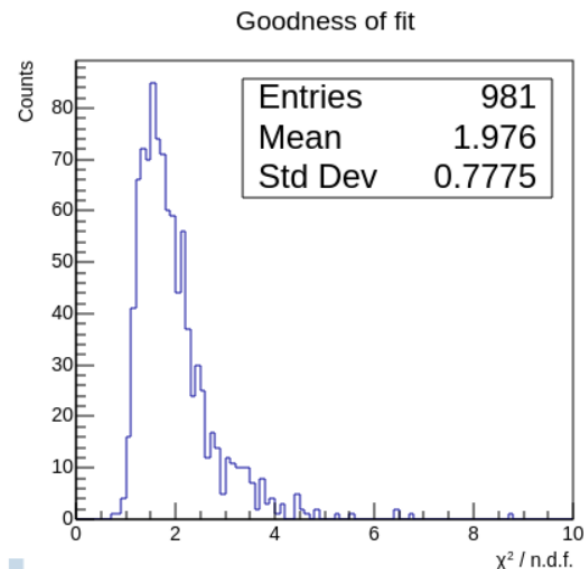
$$f(t|A, B, b_r, \delta_1, \sigma, s_m, t_0, \tau) = \frac{A(e^{-\frac{t-t_0}{\tau}} - B e^{-\frac{t-t_0}{\tau \cdot b_r}})}{(1 + e^{-\frac{t-t_0}{\sigma}})(1 + e^{-\frac{t-t_0-\delta_1}{\sigma \cdot s_m}})}$$



Signal model on first dataset



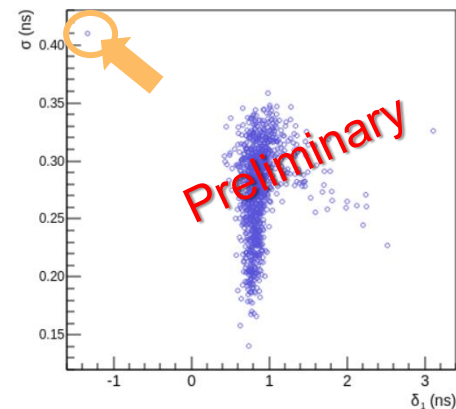
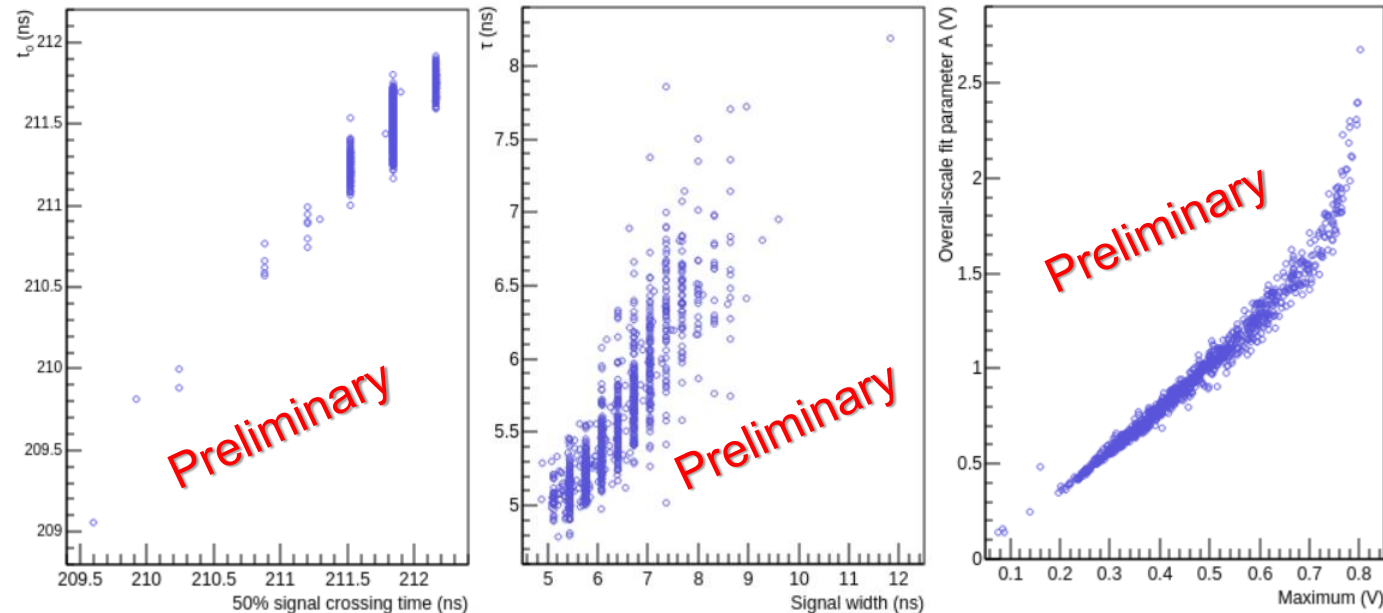
- Fit quite successful (98.2%) on the first bunch of waveform before high rate irradiation



First low rate dataset analysis

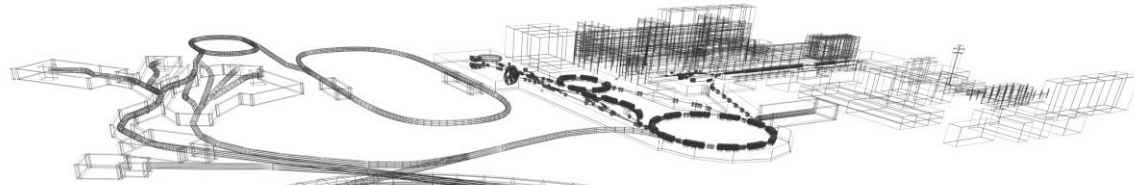
- Correlation between shape descriptors and fit parameters

- Correlation among fit parameters



$$\frac{A(e^{-\frac{t-t_0}{\tau}} - Be^{-\frac{t-t_0}{\tau \cdot br}})}{(1 + e^{-\frac{t-t_0}{\sigma}})(1 + e^{-\frac{t-t_0-\delta_1}{\sigma \cdot sm}})}$$

- Process and analyze waveforms from another bunch with the same conditions (low rate, -300V HV, ...), after the high rate irradiation period → ongoing
- Calculate the integrated ions after the high rate irradiation until this second bunch (right now rough estimate of $8 \cdot 10^9$ ions/mm² for the whole test) → next step
- Extend this analysis to the irradiation test in March, performed with U beam



**Many thanks to Chiara, Michael,
Mladen, Joshua, ...**

... and thanks for your attention!